

Plastronics

H033-04 contact
DC Measurement Results

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3/26/2012

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Objective

The objective of these measurements is to determine the DC performance of a Plastronics H033-04 contact. Measurements are to determine current carrying ability.

Methodology

A four terminal (Kelvin) measurement setup is used that includes a computer controlled voltage source capable of delivering 10 A. The voltage developed across the contact is measured with a HP 3456A DMM and yields a V-I record. A 4 terminal setup (Kelvin measurement) setup is used and the DMM is operated in compensated mode to remove the effects of thermo-electric voltages due to dissimilar metals.

For the current handling tests the temperature rise in the center of the pin is measured with a thermocouple as drive current levels are gradually increased.

Test procedures

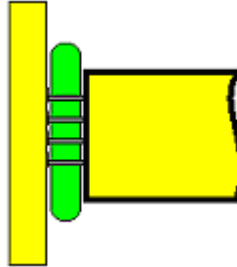


Figure 1 Test setup

During I-V testing, the z value is adjusted to nominal operating position and drive current is increased in steps of 0.05 A up to the maximum tolerable level. The dwell time for each current step is 1 s for V/I curves. Once the data are available, they are processed to reveal the resistance, power dissipation and temperature as a function of drive current.

Setup

The H033-04 contact is installed in a small test socket which is attached to an Au covered brass base plate (see Fig.2). Testing is performed in a setup similar to the one shown in Fig. 3:

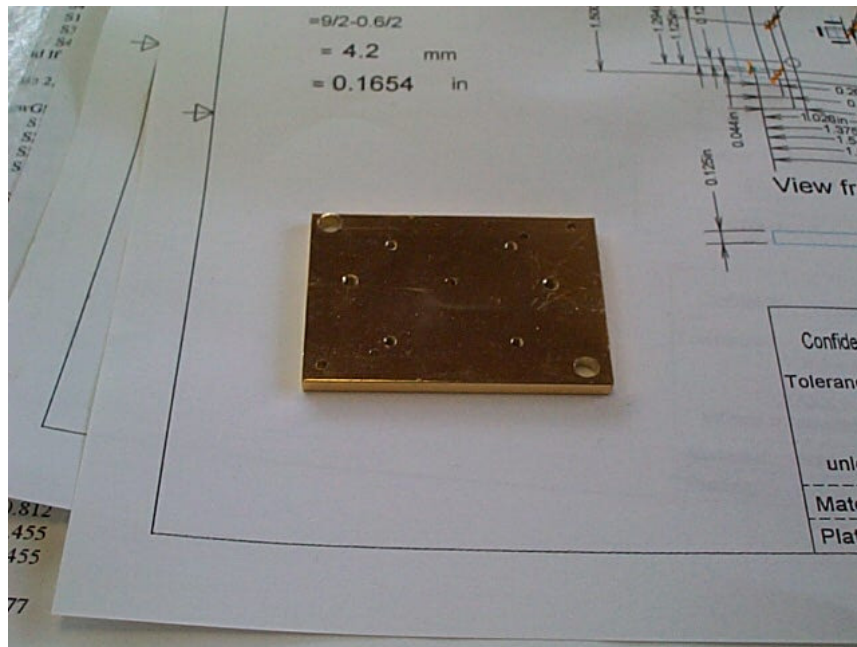


Figure 2 H033-04 contact mounting plate example

Au over Ni plating was applied to the surfaces of the brass plate. Material type and thickness specifications were identical to those used for PCBs.

The current/voltage probe consists of a copper post with suitably shaped surface. This surface is Ni and Au plated. The post has two connections, thus allowing for a four terminal measurement with very low residual resistance (about 1 milliOhm).

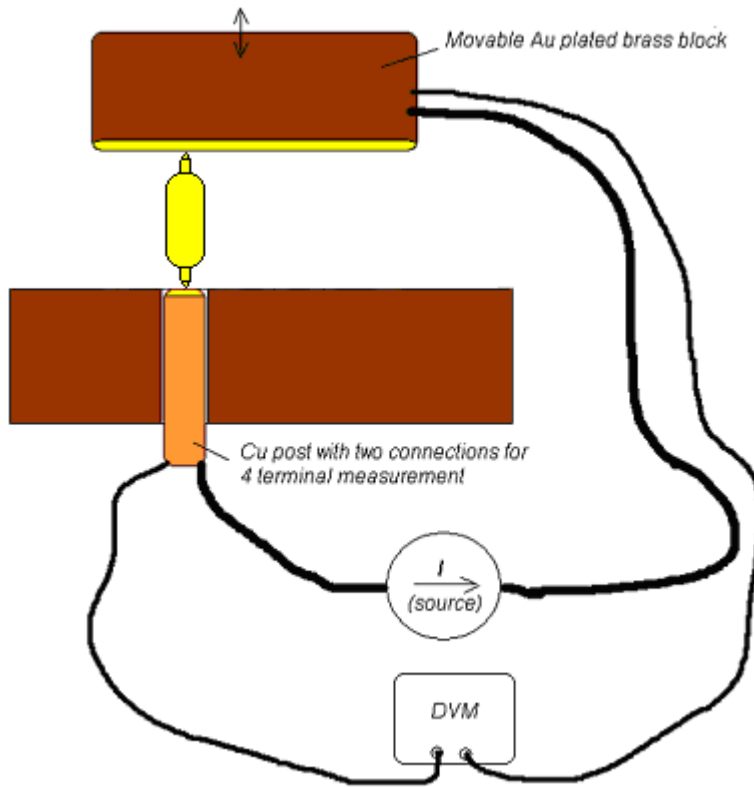


Figure 3 Test setup for 4 terminal (Kelvin) measurements

It should be kept in mind that in this setup the spring probe presses against two surfaces that are very well heat sunk.

The DUT with its plate is mounted in a test stand with XYZ adjustment capability:

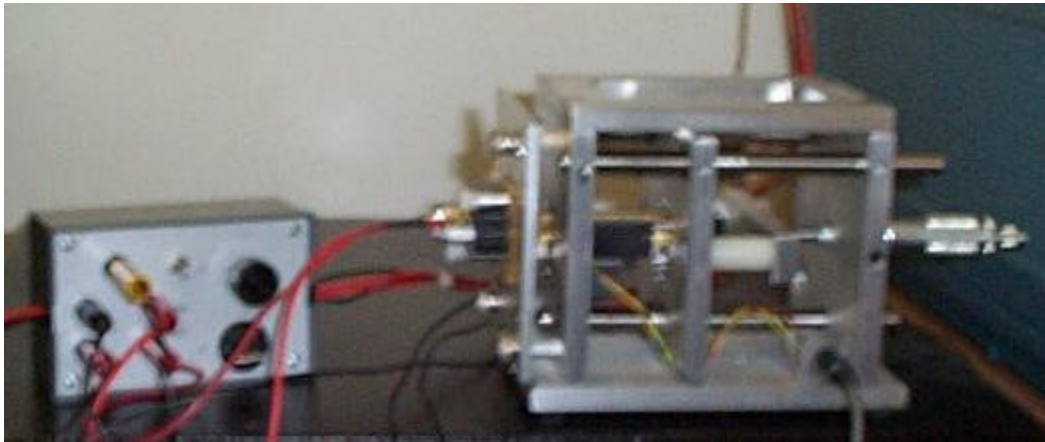


Figure 4 Test stand

This setup has a micrometer screw that allows repeatable adjustments in the Z direction. Also included is a transducer that converts Z position to an electrical signal for the data acquisition.

Measurements

Current carrying capability

The measured current – voltage relationship for two Plastronics H033-04 contacts is recorded for a gradually increasing drive current:

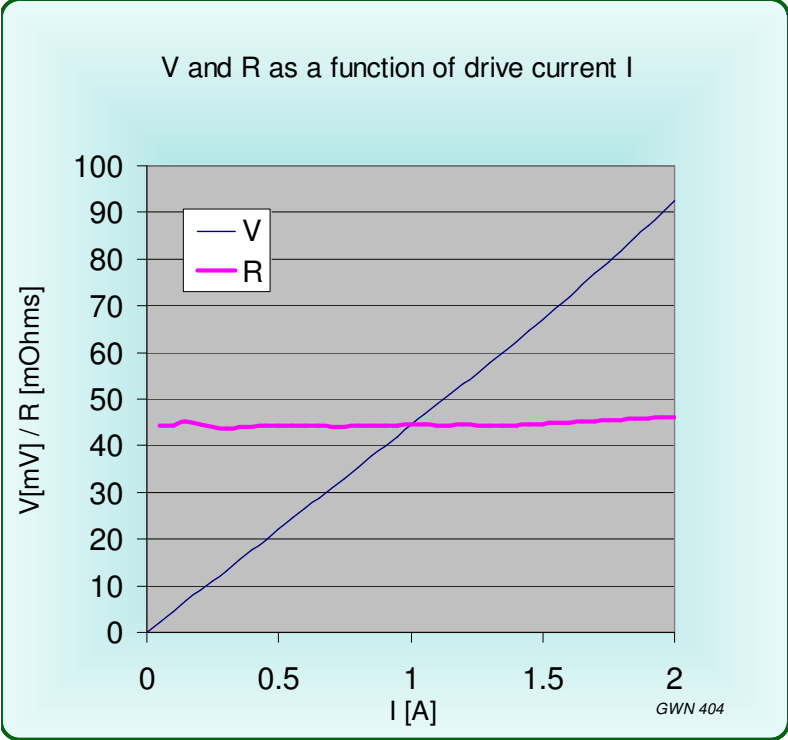


Figure 5 Voltage and resistance as a function of drive current

There are no anomalies in the response. Also of interest is power dissipation in the contact and a derivative plot (see below).

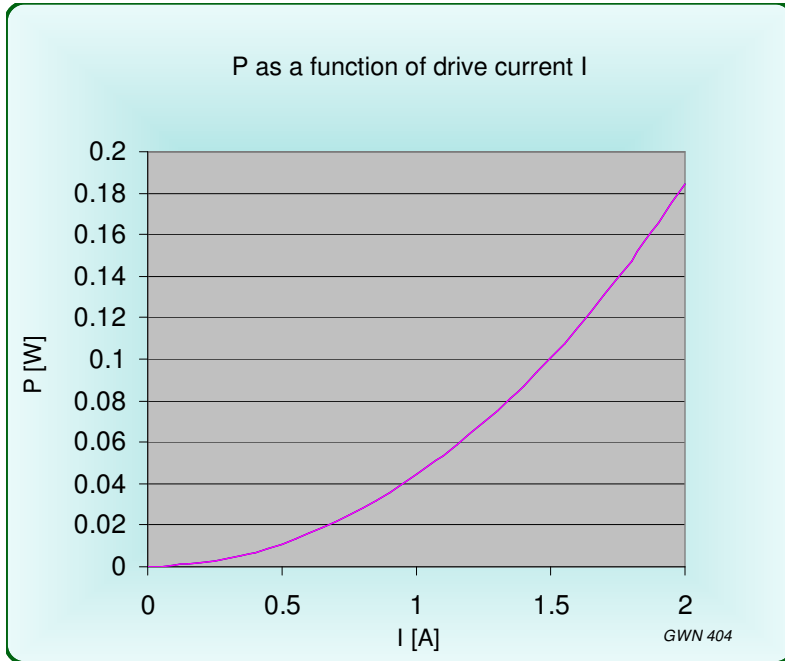


Figure 6 Power dissipation as a function of drive current

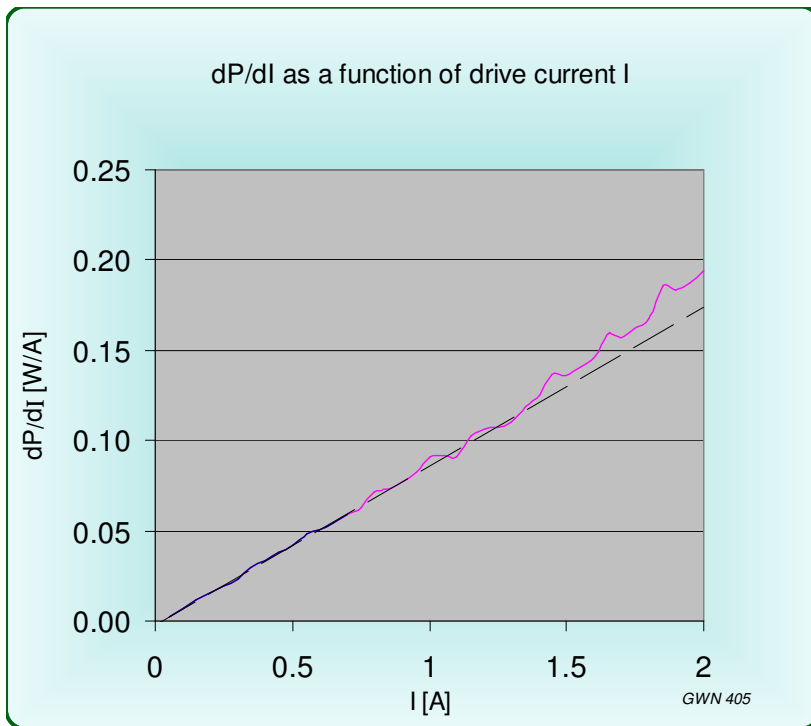


Figure 7 Derivative power dissipation as a function of drive current

Power dissipation follows a square law up to a current value of 1.4 A.

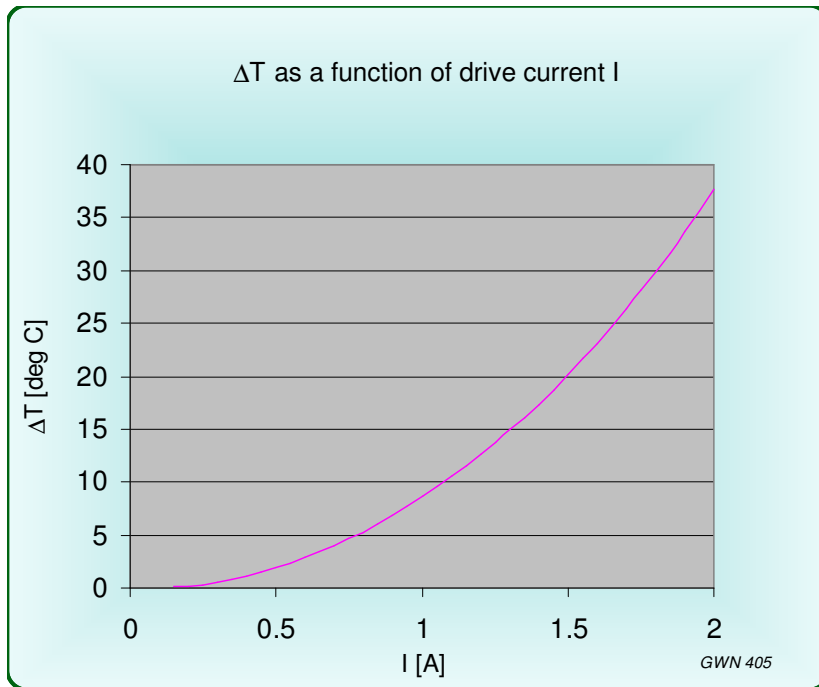


Figure 8 Temperature rise as a function of drive current

The temperature rise above ambient increases as drive currents increase. It reaches 20 C at a current level of 1.45 A. A derivative plot is shown in Figure 9 :

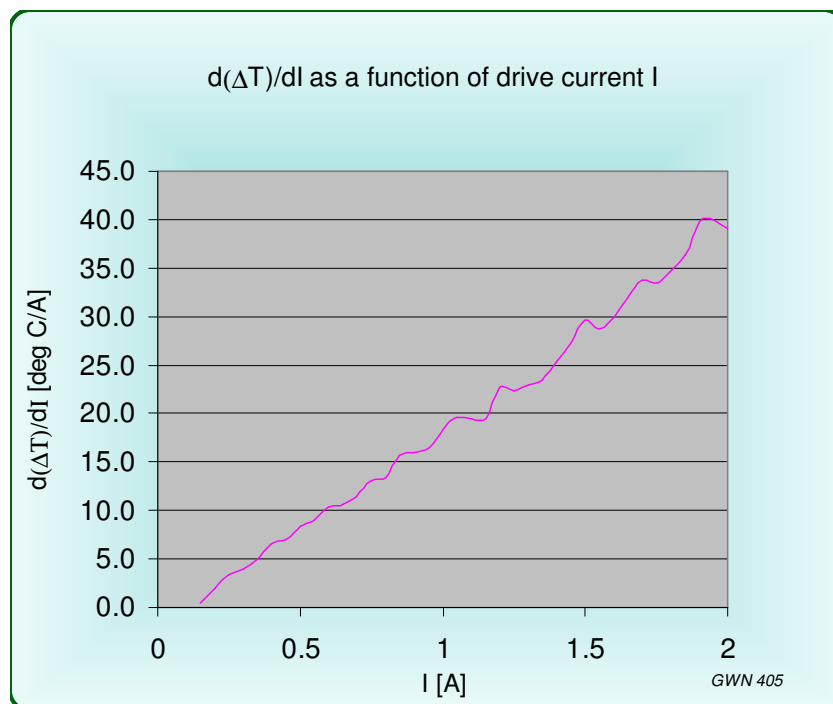


Figure 9 Derivative temperature rise as a function of drive current